

MT40G006CN5

N-Channel Enhancement Mode Power MOSFET

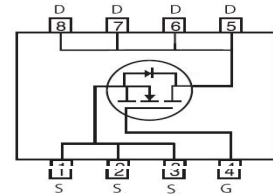


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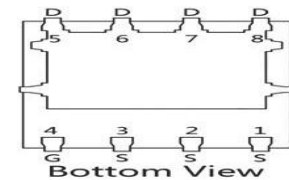
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V_{DS}	40	V
$R_{DS(on),TYP@V_{GS}=10V}$	0.58	mΩ
I_D (Silicon Limited)	450	A

Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



Features

- Enhancement mode
- Ultra Low $R_{DS(on)}$ to minimize conduction losses
- 100% Avalanche Tested, 100% R_g Tested
- Optimized Q_g , Q_{gd} , and Q_{gd}/Q_{gs} ratio to minimize switching losses

Maximum ratings, at $T_A = 25^\circ\text{C}$, unless otherwise specified

Symbol	Parameter	Rating	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	40	V
V_{GS}	Gate-source voltage	± 20	V
I_S	Diode continuous forward current	$T_C = 25^\circ\text{C}$ 266	A
I_D	Continuous drain current @ $V_{GS}=10\text{V}$ (Silicon limited)	$T_C = 25^\circ\text{C}$ 450	A
I_D	Continuous drain current @ $V_{GS}=10\text{V}$ (Silicon limited)	$T_C = 100^\circ\text{C}$ 285	A
I_{DM}	Pulse drain current tested ①	$T_C = 25^\circ\text{C}$ 980	A
I_{DSM}	Continuous drain current @ $V_{GS}=10\text{V}$	$T_A = 25^\circ\text{C}$ 45	A
		$T_A = 70^\circ\text{C}$ 36	A
E_{AS}	Avalanche energy, single pulsed ②	1024	mJ
P_D	Maximum power dissipation ③	$T_C = 25^\circ\text{C}$ 266	W
		$T_C = 100^\circ\text{C}$ 106	W
P_{DSM}	Maximum power dissipation ④	$T_A = 25^\circ\text{C}$ 2.6	W
		$T_A = 70^\circ\text{C}$ 1.7	W
T_J, T_{STG}	Operating junction and storage temperature range	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typical	Max	Unit
$R_{\theta JC}$	Thermal resistance, junction-to-case ⑤	0.39	0.47	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal resistance, junction-to-ambient ⑥	40	48	$^\circ\text{C}/\text{W}$

Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ T_J=25°C (unless otherwise stated)						
V _{(BR)DSS}	Drain-source breakdown voltage	V _{GS} =0V, I _D =250μA	40	--	--	V
I _{DSS}	Zero gate voltage drain current(T _J =25°C)	V _{DS} =40V, V _{GS} =0V	--	--	1	μA
	Zero gate voltage drain current(T _J =125°C) ^⑦	V _{DS} =40V, V _{GS} =0V	--	--	100	μA
I _{GSS}	Gate-body leakage current	V _{GS} =±20V, V _{DS} =0V	--	--	±100	nA
V _{GS(th)}	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250μA	2.4	3	3.6	V
R _{DS(on)}	Drain-source on-state resistance ^⑧	V _{GS} =10V, I _D =40A	--	0.58	0.8	mΩ
		(T _J =100°C) ^⑦	--	0.79	--	mΩ
G _{FS}	Forward transconductance	V _{DS} =5V, I _D =40A	--	138	--	S
Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
C _{iss}	Input capacitance ^⑦	V _{DS} =20V, V _{GS} =0V, f=100kHz	--	8645	--	pF
C _{oss}	Output capacitance ^⑦		--	2125	--	pF
C _{rss}	Reverse transfer capacitance ^⑦		--	130	--	pF
R _g	Gate resistance	f=1MHz	--	3.1	--	Ω
Q _g	Total gate charge ^⑦	V _{DS} =20V, I _D =40A, V _{GS} =10V	--	117	--	nC
Q _{gs}	Gate-source charge ^⑦		--	34	--	nC
Q _{gd}	Gate-drain charge ^⑦		--	16	--	nC
Switching Characteristics ^⑦						
T _{d(on)}	Turn-on delay time	V _{DD} =20V, I _D =40A, R _G =3Ω, V _{GS} =10V	--	13	--	ns
T _r	Turn-on rise time		--	73	--	ns
T _{d(off)}	Turn-off delay time		--	93	--	ns
T _f	Turn-off fall time		--	57	--	ns
Source- Drain Diode Characteristics@ T_J = 25°C (unless otherwise stated)						
V _{SD}	Forward on voltage	I _{SD} =40A, V _{GS} =0V	--	0.77	1	V
T _{rr}	Reverse recovery time ^⑦	V _{DD} =30V, I _{sd} =40A, V _{GS} =0V	--	54	--	ns
Q _{rr}	Reverse recovery charge ^⑦	di/dt=100A/μs	--	52	--	nC

NOTE:

- ① Single pulse; pulse width ≤ 100μs.
- ② This value is based on starting T_J = 25°C, L = 0.5mH, R_G = 25Ω, I_{AS} = 64A, V_{GS} = 10V; 100% FT tested at L = 0.1mH, I_{AS} = 65A.
- ③ The power dissipation P_d is based on T_{J(max)}, using junction-to-case thermal resistance R_{θJC}.
- ④ The power dissipation P_{dsm} is based on T_{J(max)}, using junction-to-ambient thermal resistance R_{θJA}.
- ⑤ Thermal resistance from junction to soldering point (on the exposed drain pad). These tests are performed on a cold plate.
- ⑥ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C.
- ⑦ Guaranteed by design, not subject to production testing.
- ⑧ Pulse width ≤ 380μs; duty cycles ≤ 2%.

Typical Characteristics

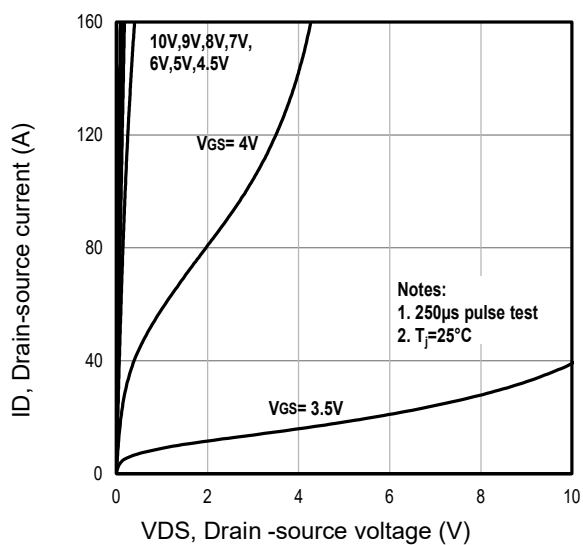


Fig1. Typical output characteristics

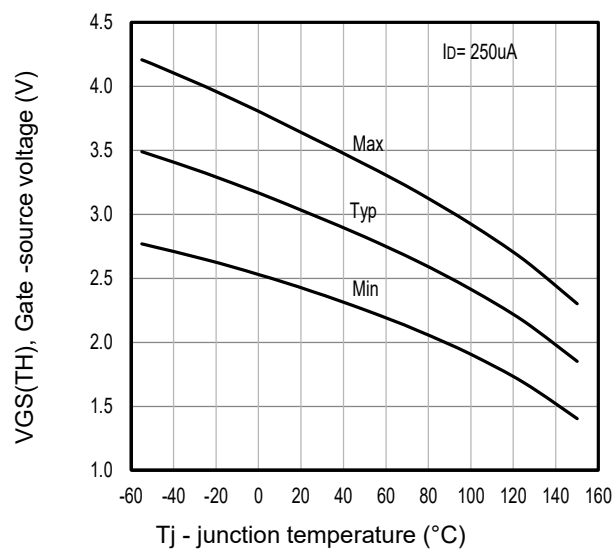


Fig2. Typical $V_{GS(TH)}$ gate-source voltage Vs. T_j

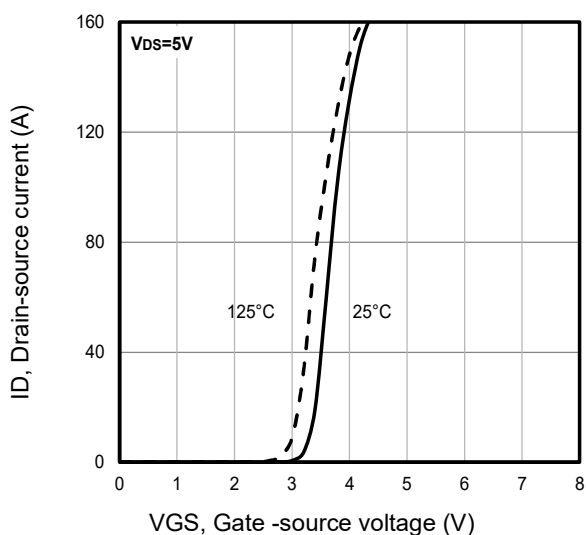


Fig3. Typical transfer characteristics

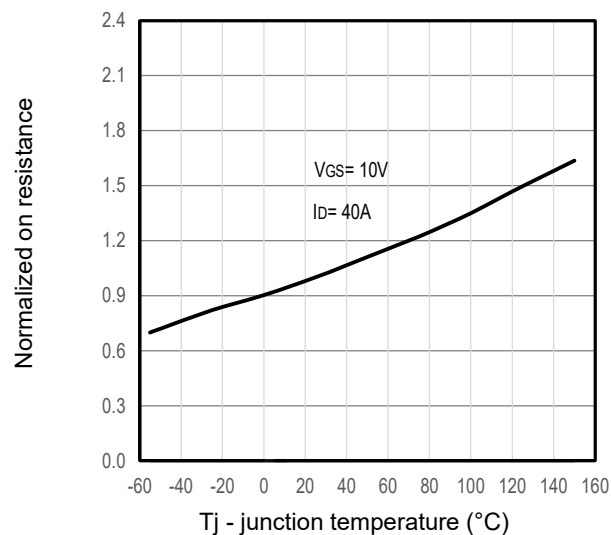


Fig4. Typical normalized on-resistance Vs. T_j

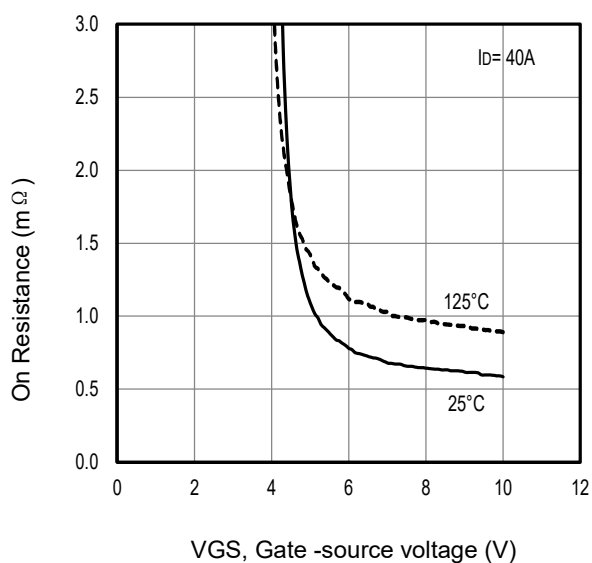


Fig5. Typical on-resistance Vs gate-source voltage

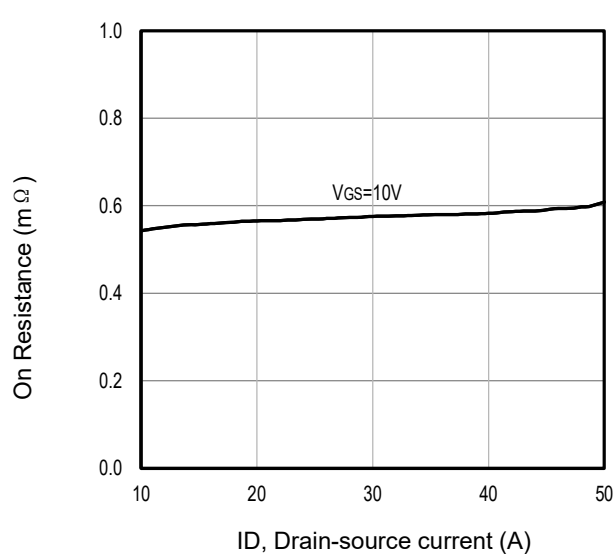


Fig6. Typical on-resistance Vs drain current

Typical Characteristics

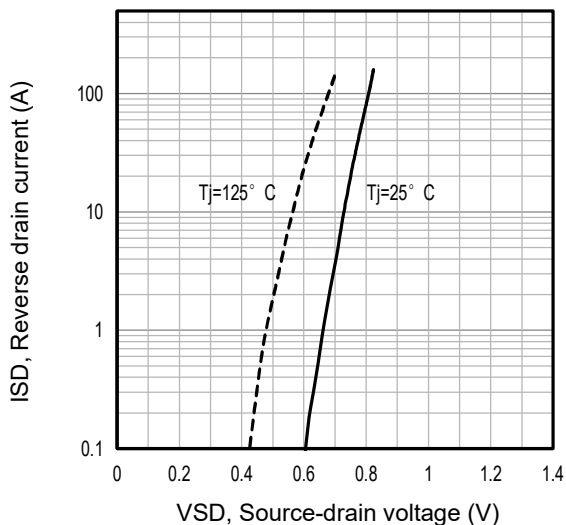


Fig7. Typical source-drain diode forward voltage

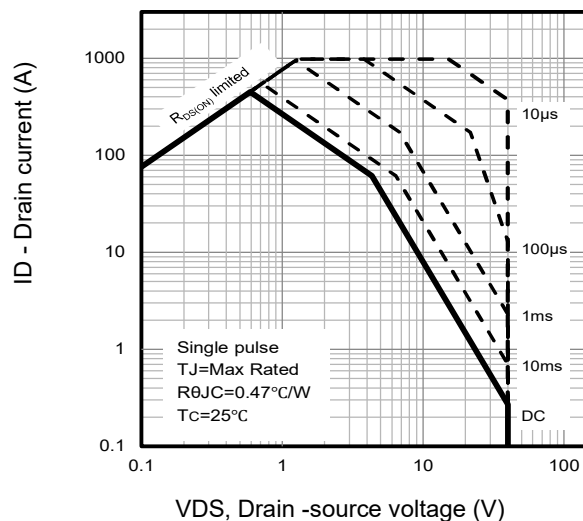


Fig8. Maximum safe operating area

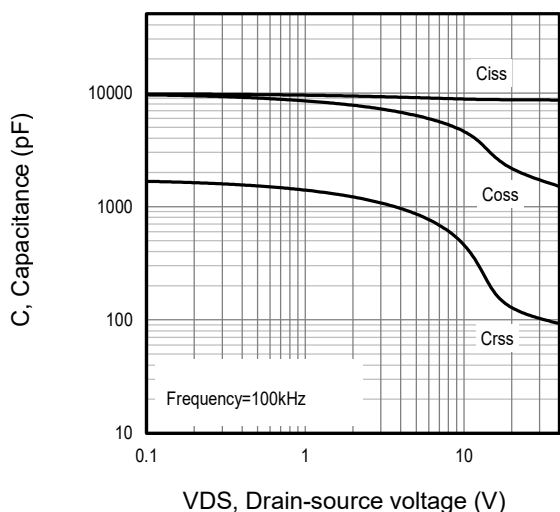


Fig9. Typical capacitance Vs. drain-source voltage

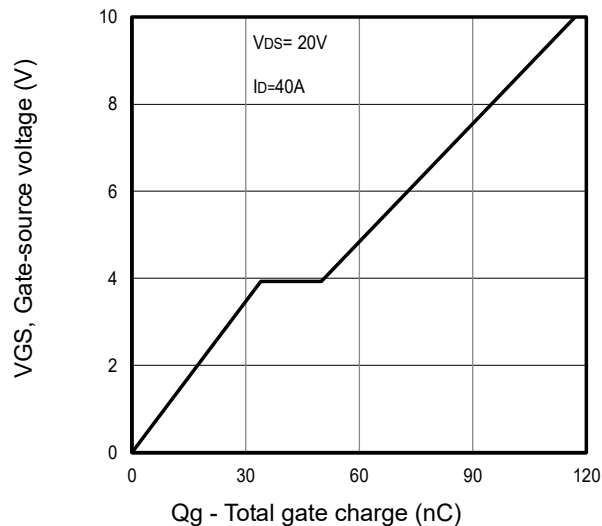


Fig10. Typical gate charge Vs. gate-source voltage

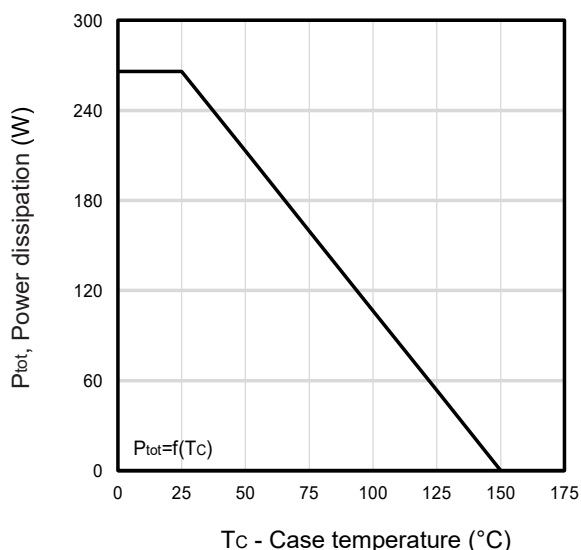


Fig11. Power dissipation Vs. case temperature

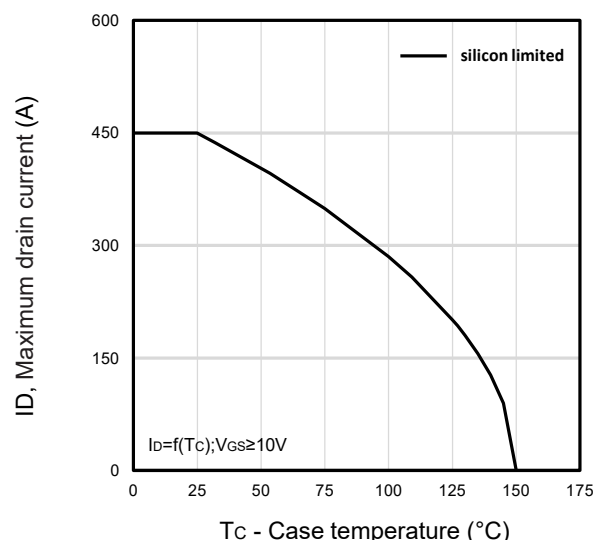


Fig12. Maximum drain current Vs. case temperature

Typical Characteristics

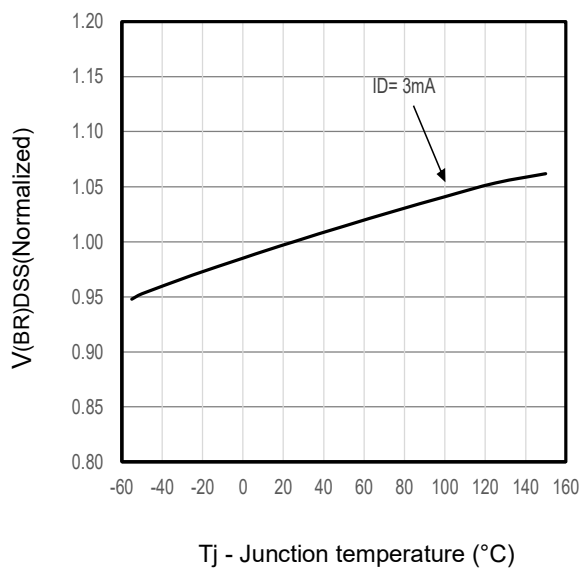


Fig13. Typical V(BR)DSS Vs Tj

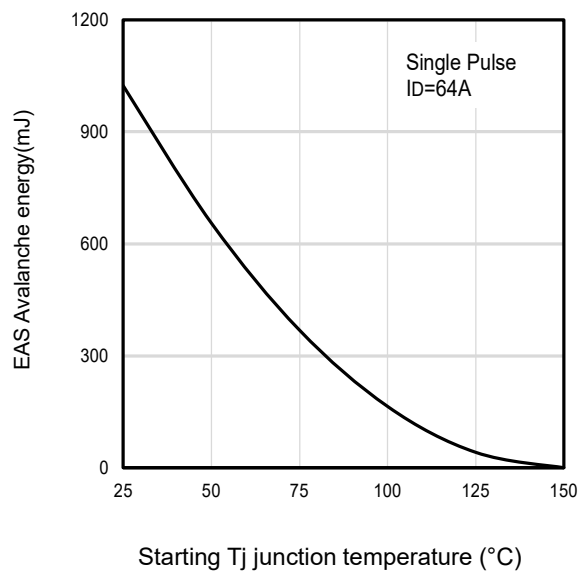


Fig14. Maximum avalanche energy vs temperature (°C)

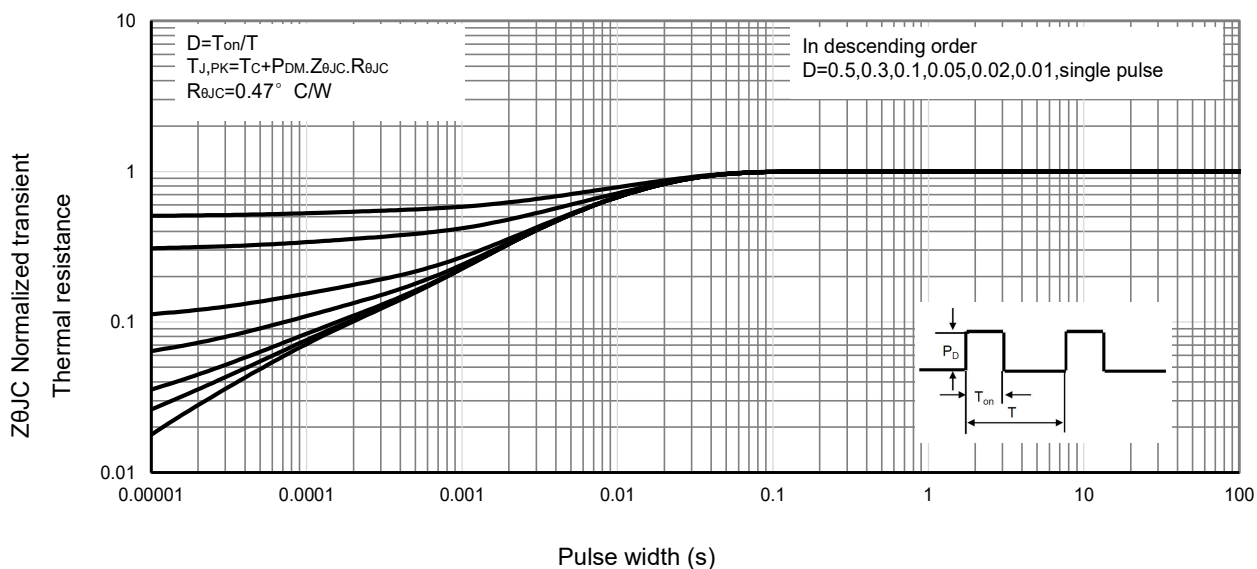


Fig15. Normalized maximum transient thermal impedance

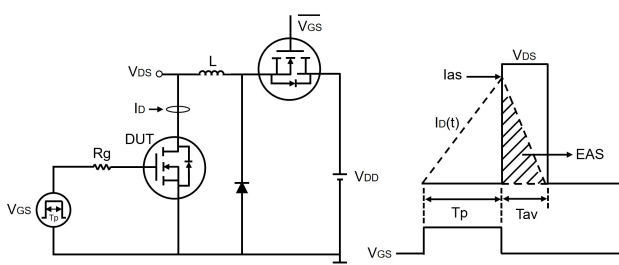


Fig16. Unclamped inductive test circuit and waveforms

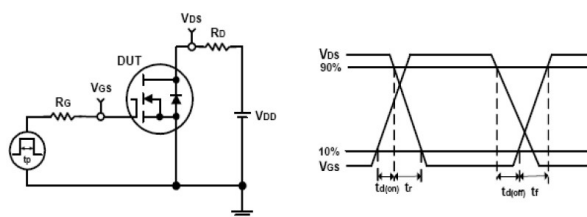
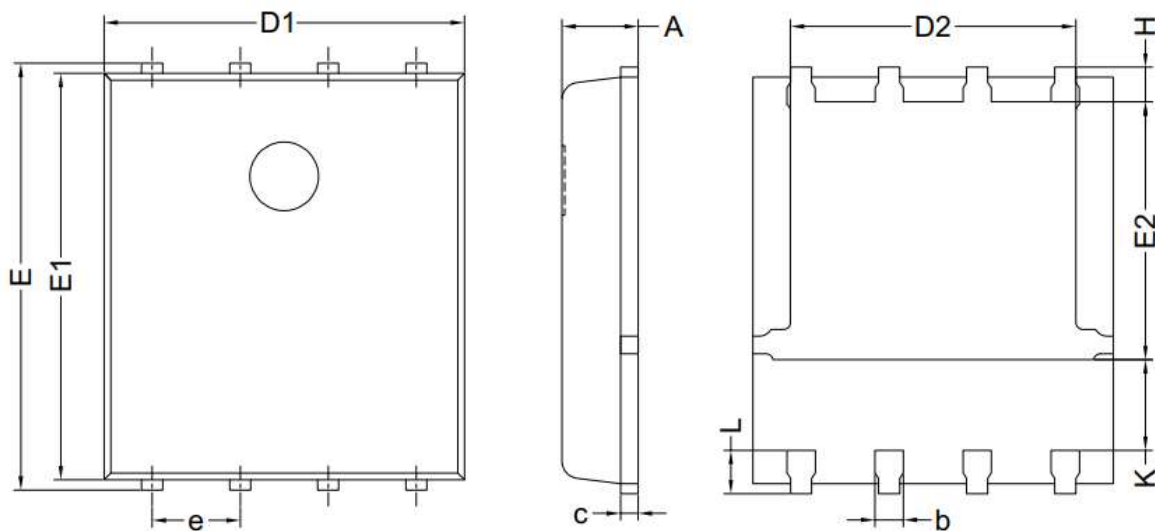
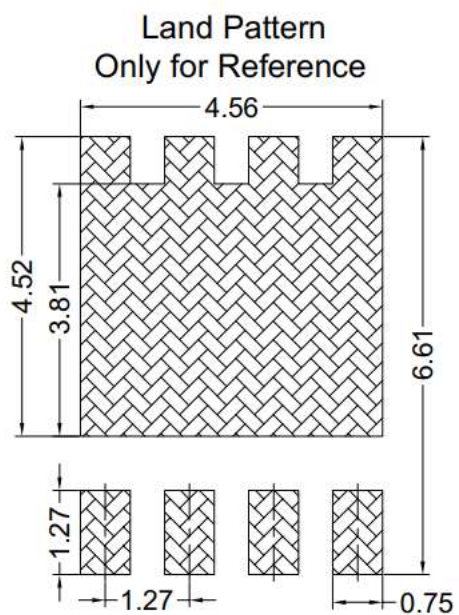


Fig17. Switching time test circuit and waveforms

PDFN5060X Package Outline Data



Symbol	DIMENSIONS (unit : mm)		
	Min	Typ	Max
A	1.00	1.10	1.20
b	0.33	0.40	0.50
c	0.20	0.25	0.30
D1	5.00	5.20	5.40
D2	3.80	4.10	4.25
e	1.27 BSC		
E	6.00	6.15	6.30
E1	5.76	5.86	5.96
E2	3.52	3.72	3.92
H	0.40	0.50	0.60
K	1.10	--	--
L	0.50	0.60	0.70



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